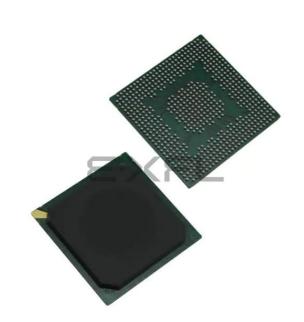
# E·XFL



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#### Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

### Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

### Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (3)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	620-BBGA Exposed Pad
Supplier Device Package	620-HBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8343evragdb

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



### NOTE

The information in this document is accurate for revision 3.x silicon and later (in other words, for orderable part numbers ending in A or B). For information on revision 1.1 silicon and earlier versions, see the *MPC8343E PowerQUICC II Pro Integrated Host Processor Hardware Specifications*.

See Section 22.1, "Part Numbers Fully Addressed by This Document," for silicon revision level determination.

## 1 Overview

This section provides a high-level overview of the device features. Figure 1 shows the major functional units within the MPC8343EA.

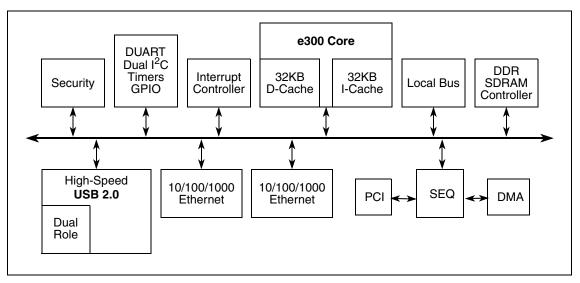


Figure 1. MPC8343EA Block Diagram

Major features of the device are as follows:

- Embedded PowerPC e300 processor core; operates at up to 400 MHz
  - High-performance, superscalar processor core
  - Floating-point, integer, load/store, system register, and branch processing units
  - 32-Kbyte instruction cache, 32-Kbyte data cache
  - Lockable portion of L1 cache
  - Dynamic power management
  - Software-compatible with the other Freescale processor families that implement Power Architecture technology
- Double data rate, DDR1/DDR2 SDRAM memory controller
  - Programmable timing supporting DDR1 and DDR2 SDRAM
  - 32- bit data interface, up to 266 MHz data rate



#### Overview

- Up to four physical banks (chip selects), each bank up to 1 Gbyte independently addressable
- DRAM chip configurations from 64 Mbits to 1 Gbit with  $\times 8/\times 16$  data ports
- Full error checking and correction (ECC) support
- Support for up to 16 simultaneous open pages (up to 32 pages for DDR2)
- Contiguous or discontiguous memory mapping
- Read-modify-write support
- Sleep-mode support for SDRAM self refresh
- Auto refresh
- On-the-fly power management using CKE
- Registered DIMM support
- 2.5-V SSTL2 compatible I/O for DDR1, 1.8-V SSTL2 compatible I/O for DDR2
- Dual three-speed (10/100/1000) Ethernet controllers (TSECs)
  - Dual controllers designed to comply with IEEE 802.3<sup>TM</sup>, 802.3u<sup>TM</sup>, 820.3x<sup>TM</sup>, 802.3z<sup>TM</sup>, 802.3ac<sup>TM</sup> standards
  - Ethernet physical interfaces:
    - 1000 Mbps IEEE Std. 802.3 RGMII, IEEE Std. 802.3z RTBI, full-duplex
    - 10/100 Mbps IEEE Std. 802.3 MII full- and half-duplex
  - Buffer descriptors are backward-compatible with MPC8260 and MPC860T 10/100 programming models
  - 9.6-Kbyte jumbo frame support
  - RMON statistics support
  - Internal 2-Kbyte transmit and 2-Kbyte receive FIFOs per TSEC module
  - MII management interface for control and status
  - Programmable CRC generation and checking
- PCI interface
  - Designed to comply with PCI Specification Revision 2.3
  - Data bus width:
    - 32-bit data PCI interface operating at up to 66 MHz
  - PCI 3.3-V compatible
  - PCI host bridge capabilities
  - PCI agent mode on PCI interface
  - PCI-to-memory and memory-to-PCI streaming
  - Memory prefetching of PCI read accesses and support for delayed read transactions
  - Posting of processor-to-PCI and PCI-to-memory writes
  - On-chip arbitration supporting five masters on PCI
  - Accesses to all PCI address spaces
  - Parity supported
  - Selectable hardware-enforced coherency



#### Power Characteristics

supplies are stable and if the I/O voltages are supplied before the core voltage, there may be a period of time that all input and output pins will actively be driven and cause contention and excessive current from 3A to 5A. In order to avoid actively driving the I/O pins and to eliminate excessive current draw, apply the core voltage ( $V_{DD}$ ) before the I/O voltage ( $GV_{DD}$ ,  $LV_{DD}$ , and  $OV_{DD}$ ) and assert PORESET before the power supplies fully ramp up. In the case where the core voltage is applied first, the core voltage supply must rise to 90% of its nominal value before the I/O supplies reach 0.7 V, see Figure 4.

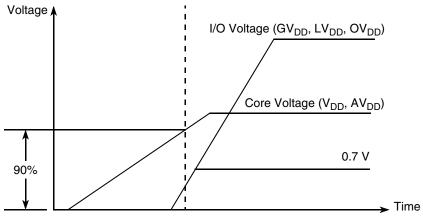


Figure 4. Power Sequencing Example

I/O voltage supplies ( $GV_{DD}$ ,  $LV_{DD}$ , and  $OV_{DD}$ ) do not have any ordering requirements with respect to one another.

## **3** Power Characteristics

The estimated typical power dissipation for the MPC8343EA device is shown in Table 4.

	Core Frequency (MHz)	CSB Frequency (MHz)	Typical at T <sub>J</sub> = 65	Typical <sup>2,3</sup>	Maximum <sup>4</sup>	Unit
PBGA	266	266	1.3	1.6	1.8	W
		133	1.1	1.4	1.6	W
	400	266	1.5	1.9	2.1	W
		133	1.4	1.7	1.9	W
	400	200	1.5	1.8	2.0	W
		100	1.3	1.7	1.9	W

 Table 4. MPC8343EA Power Dissipation<sup>1</sup>

<sup>1</sup> The values do not include I/O supply power (OV<sub>DD</sub>, LV<sub>DD</sub>, GV<sub>DD</sub>) or AV<sub>DD</sub>. For I/O power values, see Table 5.

<sup>2</sup> Typical power is based on a voltage of  $V_{DD}$  = 1.2 V, a junction temperature of  $T_J$  = 105°C, and a Dhrystone benchmark application.

<sup>3</sup> Thermal solutions may need to design to a value higher than typical power based on the end application, T<sub>A</sub> target, and I/O power.

<sup>4</sup> Maximum power is based on a voltage of V<sub>DD</sub> = 1.2 V, worst case process, a junction temperature of T<sub>J</sub> = 105°C, and an artificial smoke test.



Parameter	Condition	Symbol	Min	Мах	Unit
PCI_SYNC_IN input current	$\begin{array}{c} 0 \ V \leq V_{IN} \leq 0.5 \ V \ or \\ OV_{DD} - 0.5 \ V \leq V_{IN} \leq OV_{DD} \end{array}$	I <sub>IN</sub>	_	±10	μA
PCI_SYNC_IN input current	$0.5~V \leq V_{IN} \leq OV_{DD} - 0.5~V$	I <sub>IN</sub>	_	±50	μA

Table 6. CLKIN DC Timing Specifications (continued)

## 4.2 AC Electrical Characteristics

The primary clock source for the MPC8343EA can be one of two inputs, CLKIN or PCI\_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Table 7 provides the clock input (CLKIN/PCI\_CLK) AC timing specifications for the device.

**Table 7. CLKIN AC Timing Specifications** 

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
CLKIN/PCI_CLK frequency	f <sub>CLKIN</sub>	_	—	66	MHz	1, 6
CLKIN/PCI_CLK cycle time	t <sub>CLKIN</sub>	15	_	_	ns	_
CLKIN/PCI_CLK rise and fall time	t <sub>KH</sub> , t <sub>KL</sub>	0.6	1.0	2.3	ns	2
CLKIN/PCI_CLK duty cycle	t <sub>KHK</sub> ∕t <sub>CLKIN</sub>	40	_	60	%	3
CLKIN/PCI_CLK jitter	—			±150	ps	4, 5

### Notes:

1. **Caution:** The system, core, USB, security, and TSEC must not exceed their respective maximum or minimum operating frequencies.

- 2. Rise and fall times for CLKIN/PCI\_CLK are measured at 0.4 and 2.7 V.
- 3. Timing is guaranteed by design and characterization.
- 4. This represents the total input jitter—short term and long term—and is guaranteed by design.
- 5. The CLKIN/PCI\_CLK driver's closed loop jitter bandwidth should be < 500 kHz at -20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track CLKIN drivers with the specified jitter.
- 6. Spread spectrum clocking is allowed with 1% input frequency down-spread at maximum 50 KHz modulation rate regardless of input frequency.

## 4.3 TSEC Gigabit Reference Clock Timing

Table 8 provides the TSEC gigabit reference clocks (EC\_GTX\_CLK125) AC timing specifications.

### Table 8. EC\_GTX\_CLK125 AC Timing Specifications

At recommended operating conditions with LV  $_{DD}$  = 2.5  $\pm$  0.125 mV/ 3.3 V  $\pm$  165 mV

Parameter	Symbol	Min	Typical	Max	Unit	Notes
EC_GTX_CLK125 frequency	t <sub>G125</sub>	-	125	_	MHz	—
EC_GTX_CLK125 cycle time	t <sub>G125</sub>		8		ns	—
EC_GTX_CLK125 rise and fall time $\label{eq:LV_DD} \begin{array}{l} \text{LV}_{\text{DD}} = 2.5 \text{ V} \\ \text{LV}_{\text{DD}} = 3.3 \text{ V} \end{array}$	t <sub>G125R</sub> /t <sub>G125F</sub>	_		0.75 1.0	ns	1



**RESET** Initialization

## 5.2 **RESET AC Electrical Characteristics**

Table 10 provides the reset initialization AC timing specifications of the MPC8343EA.

### Table 10. RESET Initialization Timing Specifications

Parameter	Min	Max	Unit	Notes
Required assertion time of HRESET or SRESET (input) to activate reset flow	32	—	t <sub>PCI_SYNC_IN</sub>	1
Required assertion time of $\overrightarrow{\text{PORESET}}$ with stable clock applied to CLKIN when the MPC8343EA is in PCI host mode		-	t <sub>CLKIN</sub>	2
Required assertion time of PORESET with stable clock applied to PCI_SYNC_IN when the MPC8343EA is in PCI agent mode	32	_	t <sub>PCI_SYNC_IN</sub>	1
HRESET/SRESET assertion (output)	512	_	t <sub>PCI_SYNC_IN</sub>	1
HRESET negation to SRESET negation (output)	16	_	t <sub>PCI_SYNC_IN</sub>	1
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of PORESET when the MPC8343EA is in PCI host mode	4	—	t <sub>CLKIN</sub>	2
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of PORESET when the MPC8343EA is in PCI agent mode	4	—	t <sub>PCI_SYNC_IN</sub>	1
Input hold time for POR configuration signals with respect to negation of HRESET	0	—	ns	—
Time for the MPC8343EA to turn off POR configuration signals with respect to the assertion of HRESET	_	4	ns	3
Time for the MPC8343EA to turn on POR configuration signals with respect to the negation of HRESET	1	_	t <sub>PCI_SYNC_IN</sub>	1, 3

Notes:

1. t<sub>PCI\_SYNC\_IN</sub> is the clock period of the input clock applied to PCI\_SYNC\_IN. In PCI host mode, the primary clock is applied to the CLKIN input, and PCI\_SYNC\_IN period depends on the value of CFG\_CLKIN\_DIV. See the *MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual*.

2. t<sub>CLKIN</sub> is the clock period of the input clock applied to CLKIN. It is valid only in PCI host mode. See the MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual.

3. POR configuration signals consist of CFG\_RESET\_SOURCE[0:2] and CFG\_CLKIN\_DIV.

### Table 11 lists the PLL and DLL lock times.

### Table 11. PLL and DLL Lock Times

Parameter/Condition	Min	Мах	Unit	Notes
PLL lock times	_	100	μs	—
DLL lock times	7680	122,880	csb_clk cycles	1, 2

Notes:

1. DLL lock times are a function of the ratio between the output clock and the coherency system bus clock (csb\_clk). A 2:1 ratio results in the minimum and an 8:1 ratio results in the maximum.

2. The csb\_clk is determined by the CLKIN and system PLL ratio. See Section 19, "Clocking."



#### DDR and DDR2 SDRAM

Table 16 provides the current draw characteristics for  $MV_{REF}$ .

Table 16. Current Draw Characteristics for MV<sub>REF</sub>

Parameter/Condition	Symbol	Min	Max	Unit	Note
Current draw for MV <sub>REF</sub>	I <sub>MVREF</sub>		500	μA	1

Note:

1. The voltage regulator for  $\text{MV}_{\text{REF}}$  must supply up to 500  $\mu\text{A}$  current.

## 6.2 DDR and DDR2 SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR and DDR2 SDRAM interface.

### 6.2.1 DDR and DDR2 SDRAM Input AC Timing Specifications

Table 17 provides the input AC timing specifications for the DDR2 SDRAM when  $GV_{DD}(typ) = 1.8 \text{ V}$ .

### Table 17. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with GV\_{DD} of 1.8  $\pm$  5%.

Parameter	Symbol	Min	Мах	Unit	Notes
AC input low voltage	V <sub>IL</sub>	_	MV <sub>REF</sub> – 0.25	V	—
AC input high voltage	V <sub>IH</sub>	MV <sub>REF</sub> + 0.25	_	V	—

Table 18 provides the input AC timing specifications for the DDR SDRAM when  $GV_{DD}(typ) = 2.5 V$ .

### Table 18. DDR SDRAM Input AC Timing Specifications for 2.5-V Interface

At recommended operating conditions with  $GV_{DD}$  of 2.5  $\pm$  5%.

Parameter	Symbol	Min	Мах	Unit	Notes
AC input low voltage	V <sub>IL</sub>	—	MV <sub>REF</sub> – 0.31	V	—
AC input high voltage	V <sub>IH</sub>	MV <sub>REF</sub> + 0.31	—	V	—

Table 19 provides the input AC timing specifications for the DDR SDRAM interface.

### Table 19. DDR and DDR2 SDRAM Input AC Timing Specifications

At recommended operating conditions with  $GV_{DD}$  of (1.8 or 2.5 V) ± 5%.

Parameter	Symbol	Min	Мах	Unit	Notes
Controller Skew for MDQS—MDQ/MECC/MDM	t <sub>CISKEW</sub>			ps	1, 2
400 MHz		-600	600		3
333 MHz		-750	750		—



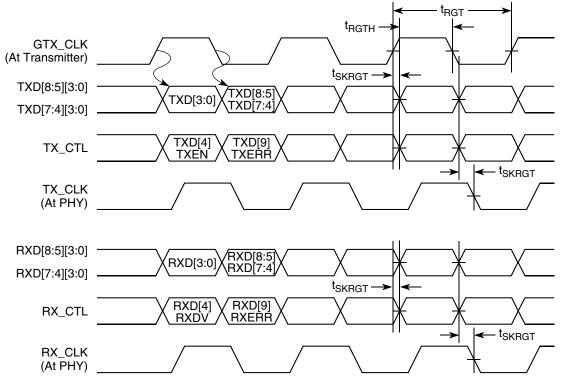


Figure 12 shows the RBMII and RTBI AC timing and multiplexing diagrams.

Figure 12. RGMII and RTBI AC Timing and Multiplexing Diagrams

### 8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to the MII management interface signals management data input/output (MDIO) and management data clock (MDC). The electrical characteristics for GMII, RGMII, TBI and RTBI are specified in Section 8.1, "Three-Speed Ethernet Controller (TSEC)—MII/RGMII/RTBI Electrical Characteristics."

### 8.3.1 MII Management DC Electrical Characteristics

The MDC and MDIO are defined to operate at a supply voltage of 2.5 or 3.3 V. The DC electrical characteristics for MDIO and MDC are provided in Table 28 and Table 29.

Parameter	Symbol	Conditions		Min	Мах	Unit
Supply voltage (2.5 V)	LV <sub>DD</sub>	—		2.37	2.63	V
Output high voltage	V <sub>OH</sub>	$I_{OH} = -1.0 \text{ mA}$	$LV_{DD} = Min$	2.00	LV <sub>DD</sub> + 0.3	V
Output low voltage	V <sub>OL</sub>	I <sub>OL</sub> = 1.0 mA	$LV_{DD} = Min$	GND – 0.3	0.40	V
Input high voltage	V <sub>IH</sub>	—	$LV_{DD} = Min$	1.7	_	V
Input low voltage	V <sub>IL</sub>	—	$LV_{DD} = Min$	-0.3	0.70	V

Table 28. MII Management DC Electrical Characteristics Powered at 2.5 V
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## 10.2 Local Bus AC Electrical Specification

Table 34 and Table 35 describe the general timing parameters of the local bus interface of the MPC8343EA.

Parameter	Symbol <sup>1</sup>	Min	Max	Unit	Notes
Local bus cycle time	t <sub>LBK</sub>	7.5		ns	2
Input setup to local bus clock (except LUPWAIT)	t <sub>LBIVKH1</sub>	1.5	—	ns	3, 4
LUPWAIT input setup to local bus clock	t <sub>LBIVKH2</sub>	2.2	—	ns	3, 4
Input hold from local bus clock (except LUPWAIT)	t <sub>LBIXKH1</sub>	1.0	—	ns	3, 4
LUPWAIT Input hold from local bus clock	t <sub>LBIXKH2</sub>	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT1</sub>	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT2</sub>	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT3</sub>	2.5	—	ns	7
Local bus clock to LALE rise	t <sub>LBKHLR</sub>		4.5	ns	—
Local bus clock to output valid (except LAD/LDP and LALE)	t <sub>LBKHOV1</sub>		4.5	ns	—
Local bus clock to data valid for LAD/LDP	t <sub>LBKHOV2</sub>		4.5	ns	3
Local bus clock to address valid for LAD	t <sub>LBKHOV3</sub>		4.5	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	t <sub>LBKHOX1</sub>	1	—	ns	3
Output hold from local bus clock for LAD/LDP	t <sub>LBKHOX2</sub>	1	—	ns	3
Local bus clock to output high impedance for LAD/LDP	t <sub>LBKHOZ</sub>	_	3.8	ns	8

### Table 34. Local Bus General Timing Parameters—DLL On

### Notes:

The symbols for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state)</sub> for outputs. For example, t<sub>LBIXKH1</sub> symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t<sub>LBK</sub> clock reference (K) goes high (H), in this case for clock one (1). Also, t<sub>LBKHOX</sub> symbolizes local bus timing (LB) for the t<sub>LBK</sub> clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
</sub>

- 2. All timings are in reference to the rising edge of LSYNC\_IN.
- 3. All signals are measured from  $OV_{DD}/2$  of the rising edge of LSYNC\_IN to 0.4 ×  $OV_{DD}$  of the signal in question for 3.3 V signaling levels.
- 4. Input timings are measured at the pin.
- 5. t<sub>LBOTOT1</sub> should be used when RCWH[LALE] is not set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
- 6. t<sub>LBOTOT2</sub> should be used when RCWH[LALE] is set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
- 7. t<sub>LBOTOT3</sub> should be used when RCWH[LALE] is set and when the load on the LALE output pin equals the load on the LAD output pins.
- 8. For active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to that of the leakage current specification.

Parameter	Symbol <sup>1</sup>	Min	Max	Unit	Notes
Local bus cycle time	t <sub>LBK</sub>	15	_	ns	2
Input setup to local bus clock	t <sub>LBIVKH</sub>	7	_	ns	3, 4
Input hold from local bus clock	t <sub>LBIXKH</sub>	1.0	_	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT1</sub>	1.5	_	ns	5
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT2</sub>	3	_	ns	6
LALE output fall to LAD output transition (LATCH hold time)	t <sub>LBOTOT3</sub>	2.5	_	ns	7
Local bus clock to output valid	t <sub>LBKLOV</sub>		3	ns	3
Local bus clock to output high impedance for LAD/LDP	t <sub>LBKHOZ</sub>		4	ns	8

### Table 35. Local Bus General Timing Parameters—DLL Bypass<sup>9</sup>

### Notes:

The symbols for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t<sub>(first two letters of functional block)</sub>(reference)(state)(signal)(state) for outputs. For example, t<sub>LBIXKH1</sub> symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t<sub>LBK</sub> clock reference (K) goes high (H), in this case for clock one (1). Also, t<sub>LBKHOX</sub> symbolizes local bus timing (LB) for the t<sub>LBK</sub> clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
</sub>

- 2. All timings are in reference to the falling edge of LCLK0 (for all outputs and for LGTA and LUPWAIT inputs) or the rising edge of LCLK0 (for all other inputs).
- 3. All signals are measured from  $OV_{DD}/2$  of the rising/falling edge of LCLK0 to  $0.4 \times OV_{DD}$  of the signal in question for 3.3 V signaling levels.
- 4. Input timings are measured at the pin.
- 5. t<sub>LBOTOT1</sub> should be used when RCWH[LALE] is set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
- 6. t<sub>LBOTOT2</sub> should be used when RCWH[LALE] is not set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.the
- 7. t<sub>LBOTOT3</sub> should be used when RCWH[LALE] is not set and when the load on the LALE output pin equals to the load on the LAD output pins.
- 8. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 9. DLL bypass mode is not recommended for use at frequencies above 66 MHz.

Figure 16 provides the AC test load for the local bus.

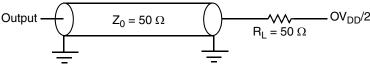


Figure 16. Local Bus C Test Load



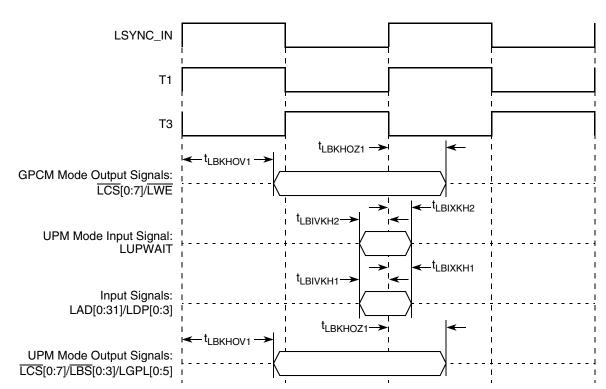


Figure 19. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Enabled)

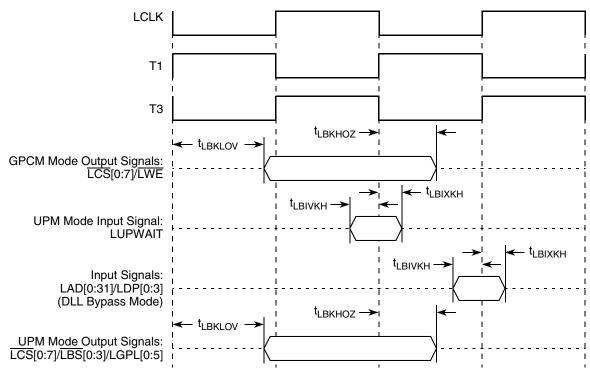


Figure 20. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Bypass Mode)



### Table 37. JTAG AC Timing Specifications (Independent of CLKIN)<sup>1</sup> (continued)

At recommended operating conditions (see Table 2).

Parameter	Symbol <sup>2</sup>	Min	Мах	Unit	Notes
JTAG external clock to output high impedance: Boundary-scan data TDO	t <sub>jtkldz</sub> t <sub>jtkloz</sub>	2 2	19 9	ns	5, 6

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of  $t_{TCLK}$  to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50  $\Omega$  load (see Figure 14). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.

2. The symbols for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state)</sub> for outputs. For example, t<sub>JTDVKH</sub> symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t<sub>JTG</sub> clock reference (K) going to the high (H) state or setup time. Also, t<sub>JTDXKH</sub> symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t<sub>JTG</sub> clock reference (K) going to the high (H) state. In general, the clock reference symbol is based on three letters representing the clock of a particular function. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).</sub>

3. TRST is an asynchronous level sensitive signal. The setup time is for test purposes only.

4. Non-JTAG signal input timing with respect to t<sub>TCLK</sub>.

5. Non-JTAG signal output timing with respect to t<sub>TCLK</sub>.

6. Guaranteed by design and characterization.

Figure 23 provides the AC test load for TDO and the boundary-scan outputs of the MPC8343EA.

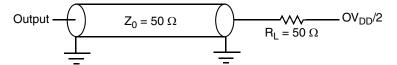


Figure 23. AC Test Load for the JTAG Interface

Figure 24 provides the JTAG clock input timing diagram.

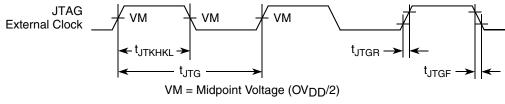


Figure 24. JTAG Clock Input Timing Diagram

Figure 25 provides the  $\overline{\text{TRST}}$  timing diagram.

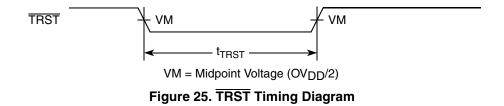




Figure 26 provides the boundary-scan timing diagram.

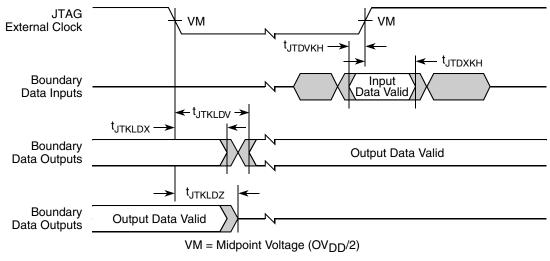
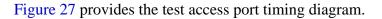


Figure 26. Boundary-Scan Timing Diagram



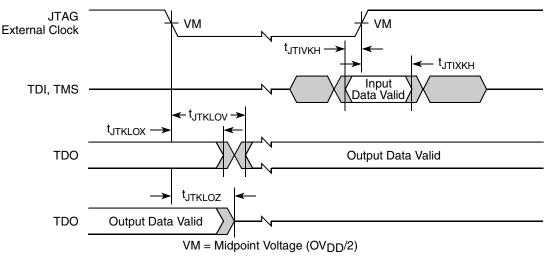


Figure 27. Test Access Port Timing Diagram



# 12 I<sup>2</sup>C

This section describes the DC and AC electrical characteristics for the I<sup>2</sup>C interface of the MPC8343EA.

## **12.1** I<sup>2</sup>C DC Electrical Characteristics

Table 38 provides the DC electrical characteristics for the I<sup>2</sup>C interface of the MPC8343EA.

### Table 38. I<sup>2</sup>C DC Electrical Characteristics

At recommended operating conditions with  $\text{OV}_{\text{DD}}$  of 3.3 V  $\pm$  10%.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V <sub>IH</sub>	$0.7 \times OV_{DD}$	OV <sub>DD</sub> + 0.3	V	—
Input low voltage level	V <sub>IL</sub>	-0.3	$0.3\times \text{OV}_{\text{DD}}$	V	_
Low level output voltage	V <sub>OL</sub>	0	$0.2\times\text{OV}_{\text{DD}}$	V	1
Output fall time from $V_{IH}(min)$ to $V_{IL}(max)$ with a bus capacitance from 10 to 400 pF	t <sub>I2KLKV</sub>	$20 + 0.1 \times C_B$	250	ns	2
Pulse width of spikes which must be suppressed by the input filter	t <sub>i2KHKL</sub>	0	50	ns	3
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}$ (max)	lı	-10	10	μA	4
Capacitance for each I/O pin	Cl	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.

2.  $C_B$  = capacitance of one bus line in pF.

3. Refer to the MPC8349EA Integrated Host Processor Family Reference Manual, for information on the digital filter used.

4. I/O pins obstruct the SDA and SCL lines if  $\ensuremath{\mathsf{OV}_{\mathsf{DD}}}$  is switched off.

## 12.2 I<sup>2</sup>C AC Electrical Specifications

Table 39 provides the AC timing parameters for the I<sup>2</sup>C interface of the MPC8343EA. Note that all values refer to  $V_{IH}(min)$  and  $V_{IL}(max)$  levels (see Table 38).

### Table 39. I<sup>2</sup>C AC Electrical Specifications

Parameter	Symbol <sup>1</sup>	Min	Мах	Unit
SCL clock frequency	f <sub>I2C</sub>	0	400	kHz
Low period of the SCL clock	t <sub>I2CL</sub>	1.3	—	μS
High period of the SCL clock	t <sub>I2CH</sub>	0.6	—	μs
Setup time for a repeated START condition	t <sub>I2SVKH</sub>	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t <sub>I2SXKL</sub>	0.6	—	μs
Data setup time	t <sub>I2DVKH</sub>	100	_	ns
Data hold time:CBUS compatible masters I <sup>2</sup> C bus devices	t <sub>i2DXKL</sub>	$\overline{0^2}$	 0.9 <sup>3</sup>	μs



GPIO

## 14.2 Timer AC Timing Specifications

Table 44 provides the timer input and output AC timing specifications.

Table 44. Timers Input AC Timing Specifications<sup>1</sup>

Parameter	Symbol <sup>2</sup>	Min	Unit
Timers inputs—minimum pulse width	t <sub>TIWID</sub>	20	ns

### Notes:

1. Input specifications are measured from the 50 percent level of the signal to the 50 percent level of the rising edge of CLKIN. Timings are measured at the pin.

2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by external synchronous logic. Timer inputs are required to be valid for at least t<sub>TIWID</sub> ns to ensure proper operation.

## 15 GPIO

This section describes the DC and AC electrical specifications for the GPIO.

## 15.1 GPIO DC Electrical Characteristics

Table 45 provides the DC electrical characteristics for the MPC8343EA GPIO.

Table 45.	GPIO	DC	Electrical	Characteristics
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PArameter	Symbol	Condition	Min	Мах	Unit
Input high voltage	V <sub>IH</sub>	—	2.0	OV <sub>DD</sub> + 0.3	V
Input low voltage	V <sub>IL</sub>	—	-0.3	0.8	V
Input current	I <sub>IN</sub>	—	_	±5	μA
Output high voltage	V <sub>OH</sub>	I <sub>OH</sub> = -8.0 mA	2.4	—	V
Output low voltage	V <sub>OL</sub>	I <sub>OL</sub> = 8.0 mA	_	0.5	V
Output low voltage	V <sub>OL</sub>	I <sub>OL</sub> = 3.2 mA	_	0.4	V

## 15.2 GPIO AC Timing Specifications

Table 46 provides the GPIO input and output AC timing specifications.

### Table 46. GPIO Input AC Timing Specifications<sup>1</sup>

Parameter	Symbol <sup>2</sup>	Min	Unit
GPIO inputs—minimum pulse width	t <sub>PIWID</sub>	20	ns

### Notes:

1. Input specifications are measured from the 50 percent level of the signal to the 50 percent level of the rising edge of CLKIN. Timings are measured at the pin.

 GPIO inputs and outputs are asynchronous to any visible clock. GPIO outputs should be synchronized before use by external synchronous logic. GPIO inputs must be valid for at least t<sub>PIWID</sub> ns to ensure proper operation.



#### Clocking

Table 53 provides the operating frequencies for the MPC8343EA PBGA under recommended operating conditions.

Parameter <sup>1</sup>	266 MHz	333 MHz	400 MHz	Unit
e300 core frequency ( <i>core_clk</i> )	200–266	200–333	200–400	MHz
Coherent system bus frequency (csb_clk)	100–266			MHz
DDR1 memory bus frequency (MCK) <sup>2</sup>		MHz		
DDR2 memory bus frequency (MCK) <sup>3</sup>		MHz		
Local bus frequency (LCLKn) <sup>4</sup>		MHz		
PCI input frequency (CLKIN or PCI_CLK)	25–66			MHz
Security core maximum internal operating frequency	133			MHz
USB_DR, USB_MPH maximum internal operating frequency	133			MHz

### Table 53. Operating Frequencies for PBGA

<sup>1</sup> The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen so that the resulting *csb\_clk*, MCLK, LCLK[0:2], and *core\_clk* frequencies do not exceed their respective maximum or minimum operating frequencies. The value of SCCR[ENCCM], SCCR[USBDRCM], and SCCR[USBMPHCM] must be programmed so that the maximum internal operating frequency of the Security core and USB modules does not exceed the respective values listed in this table.

<sup>2</sup> The DDR data rate is 2× the DDR memory bus frequency.

<sup>3</sup> The DDR data rate is 2× the DDR memory bus frequency.

<sup>4</sup> The local bus frequency is ½, ¼, or 1/8 of the *lbiu\_clk* frequency (depending on LCCR[CLKDIV]) which is in turn 1× or 2× the *csb\_clk* frequency (depending on RCWL[LBIUCM]).

## 19.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] parameter. Table 54 shows the multiplication factor encodings for the system PLL.

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10

### Table 54. System PLL Multiplication Factors



Clocking

	SPMF	<i>csb_clk</i> : Input Clock Ratio <sup>2</sup>	Input Clock Frequency (MHz) <sup>2</sup>			
CFG_CLKIN_DIV at Reset <sup>1</sup>			16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
High	0010	2:1				133
High	0011	3 : 1			100	200
High	0100	4 : 1			133	266
High	0101	5 : 1			166	333
High	0110	6 : 1			200	
High	0111	7:1			233	
High	1000	8 : 1				

### Table 55. CSB Frequency Options for Host Mode (continued)

<sup>1</sup> CFG\_CLKIN\_DIV selects the ratio between CLKIN and PCI\_SYNC\_OUT.

<sup>2</sup> CLKIN is the input clock in host mode; PCI\_CLK is the input clock in agent mode.

DDR2 memory may be used at 133 MHz provided that the memory components are specified for operation at this frequency.

### Table 56. CSB Frequency Options for Agent Mode

CFG_CLKIN_DIV at Reset <sup>1</sup>	SPMF		Input Clock Frequency (MHz) <sup>2</sup>			
		<i>csb_clk</i> : Input Clock Ratio <sup>2</sup>	16.67	25	33.33	66.67
			<i>csb_clk</i> Frequency (MHz)			
Low	0010	2 : 1				133
Low	0011	3 : 1			100	200
Low	0100	4 : 1		100	133	266
Low	0101	5 : 1		125	166	333
Low	0110	6 : 1	100	150	200	
Low	0111	7:1	116	175	233	
Low	1000	8 : 1	133	200	266	
Low	1001	9:1	150	225	300	
Low	1010	10 : 1	166	250	333	
Low	1011	11 : 1	183	275		
Low	1100	12 : 1	200	300		
Low	1101	13 : 1	216	325		
Low	1110	14 : 1	233			
Low	1111	15 : 1	250			
Low	0000	16 : 1	266			
High	0010	4 : 1		100	133	266



			Input Clock Frequency (MHz) <sup>2</sup>			
CFG_CLKIN_DIV at Reset <sup>1</sup>	SPMF	<i>csb_clk</i> : Input Clock Ratio <sup>2</sup>	16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
High	0011	6 : 1	100	150	200	
High	0100	8:1	133	200	266	
High	0101	10 : 1	166	250	333	
High	0110	12 : 1	200	300		
High	0111	14 : 1	233		]	
High	1000	16 : 1	266			

### Table 56. CSB Frequency Options for Agent Mode (continued)

<sup>1</sup> CFG\_CLKIN\_DIV doubles csb\_clk if set high.

<sup>2</sup> CLKIN is the input clock in host mode; PCI\_CLK is the input clock in agent mode.

DDR2 memory may be used at 133 MHz provided that the memory components are specified for operation at this frequency.

## **19.2 Core PLL Configuration**

RCWL[COREPLL] selects the ratio between the internal coherent system bus clock (*csb\_clk*) and the e300 core clock (*core\_clk*). Table 57 shows the encodings for RCWL[COREPLL]. COREPLL values that are not listed in Table 57 should be considered as reserved.

### NOTE

Core VCO frequency = core frequency × VCO divider

VCO divider must be set properly so that the core VCO frequency is in the range of 800–1800 MHz.

RCWL[COREPLL]		aara alku aab alk Patia	VCO Divider <sup>1</sup>		
0–1	2–5	6	<i>core_clk</i> : <i>csb_clk</i> Ratio		
nn	0000	n	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)	
00	0001	0	1:1	2	
01	0001	0	1:1	4	
10	0001	0	1:1	8	
11	0001	0	1:1	8	
00	0001	1	1.5:1	2	
01	0001	1	1.5:1	4	
10	0001	1	1.5:1	8	
11	0001	1	1.5:1	8	

### Table 57. e300 Core PLL Configuration

NP

Thermal

The junction-to-ambient thermal resistance is an industry-standard value that provides a quick and easy estimation of thermal performance. Generally, the value obtained on a single-layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity  $T_J - T_A$ ) are possible.

### 20.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter (edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

 $T_I$  = junction temperature (°C)

 $T_A$  = ambient temperature for the package (°C)

 $R_{\theta IA}$  = junction-to-ambient thermal resistance (°C/W)

 $P_D$  = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

### 20.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, use the thermal characterization parameter ( $\Psi_{JT}$ ) to determine the junction temperature and a measure of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

 $T_J$  = junction temperature (°C)

 $T_T$  = thermocouple temperature on top of package (°C)

 $\Psi_{JT}$  = junction-to-ambient thermal resistance (°C/W)

 $P_D$  = power dissipation in the package (W)

The thermal characterization parameter is measured per the JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so



 $R_{\theta JC}$  = junction-to-case thermal resistance (°C/W)

 $P_D$  = power dissipation (W)

## 21 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8343EA.

## 21.1 System Clocking

The MPC8343EA includes two PLLs:

- 1. The platform PLL generates the platform clock from the externally supplied CLKIN input. The frequency ratio between the platform and CLKIN is selected using the platform PLL ratio configuration bits as described in Section 19.1, "System PLL Configuration."
- 2. The e300 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in Section 19.2, "Core PLL Configuration."

## 21.2 PLL Power Supply Filtering

Each PLL gets power through independent power supply pins (AV<sub>DD</sub>1, AV<sub>DD</sub>2, respectively). The AV<sub>DD</sub> level should always equal to  $V_{DD}$ , and preferably these voltages are derived directly from  $V_{DD}$  through a low frequency filter scheme.

There are a number of ways to provide power reliably to the PLLs, but the recommended solution is to provide four independent filter circuits as illustrated in Figure 38, one to each of the four  $AV_{DD}$  pins. Independent filters to each PLL reduce the opportunity to cause noise injection from one PLL to the other.

The circuit filters noise in the PLL resonant frequency range from 500 kHz to 10 MHz. It should be built with surface mount capacitors with minimum effective series inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

To minimize noise coupled from nearby circuits, each circuit should be placed as closely as possible to the specific  $AV_{DD}$  pin being supplied. It should be possible to route directly from the capacitors to the  $AV_{DD}$  pin, which is on the periphery of package, without the inductance of vias.

Figure 38 shows the PLL power supply filter circuit.

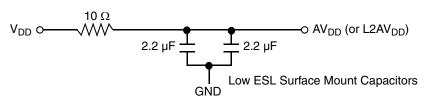


Figure 38. PLL Power Supply Filter Circuit



#### Ordering Information

However, while HRESET is asserted, these pins are treated as inputs, and the value on these pins is latched when PORESET deasserts. Then the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for the output pins.

## 21.7 Pull-Up Resistor Requirements

The MPC8343EA requires high resistance pull-up resistors (10 k $\Omega$  is recommended) on open-drain pins, including I<sup>2</sup>C pins, and IPIC interrupt pins.

For more information on required pull-up resistors and the connections required for the JTAG interface, refer to application note AN2931, "PowerQUICC Design Checklist."

## 22 Ordering Information

This section presents ordering information for the device discussed in this document, and it shows an example of how the parts are marked.

### NOTE

The information in this document is accurate for revision 3.x silicon and later (in other words, for orderable part numbers ending in A or B). For information on revision 1.1 silicon and earlier versions, see the *MPC8343E PowerQUICC II Pro Integrated Host Processor Hardware Specifications* (Document Order No. MPC8343EEC).

## 22.1 Part Numbers Fully Addressed by This Document

Table 62 shows an analysis of the Freescale part numbering nomenclature for the MPC8343EA. The individual part numbers correspond to a maximum processor core frequency. Each part number also contains a revision code that refers to the die mask revision number. For available frequency configuration